SamHop Microelectronics Corp.

STF8209

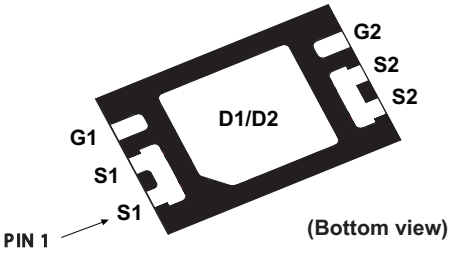
Ver 2.2

Dual N-Channel Enhancement Mode Field Effect Transistor

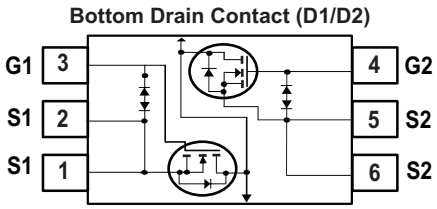
PRODUCT SUMMARY		
V_{DSS}	I_D	$R_{DS(ON)}$ (mΩ) Max
20V	6.5A	22.0 @ VGS=4.5V
		22.5 @ VGS=4.0V
		23.5 @ VGS=3.7V
		27.5 @ VGS=3.1V
		33.5 @ VGS=2.5V

FEATURES

- Super high dense cell design for low $R_{DS(ON)}$.
- Rugged and reliable.
- Suface Mount Package.
- ESD Protected.



TDFN 2X3



ABSOLUTE MAXIMUM RATINGS (T_A=25°C unless otherwise noted)

Symbol	Parameter		Limit	Units
V_{DS}	Drain-Source Voltage		20	V
V_{GS}	Gate-Source Voltage		±12	V
I_D	Drain Current-Continuous [a]	T_A=25°C	6.5	A
		T_A=70°C	5.2	A
I_{DM}	-Pulsed [b]		40	A
P_D	Maximum Power Dissipation [a]	T_A=25°C	1.56	W
		T_A=70°C	1.00	W
T_J, T_{STG}	Operating Junction and Storage Temperature Range		-55 to 150	°C

THERMAL CHARACTERISTICS

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient [a]	80	°C/W

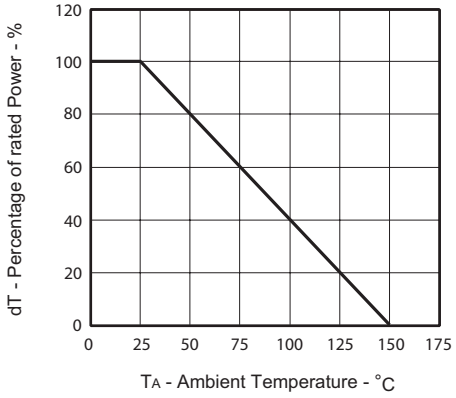
ELECTRICAL CHARACTERISTICS (T_A=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS}=0V , I_D=250uA	20			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=18V , V_{GS}=0V			1	uA
I_{GSS}	Gate-Body Leakage Current	V_{GS}= ±12V , V_{DS}=0V			±10	uA
ON CHARACTERISTICS						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} , I_D=1.0mA	0.5	0.95	1.5	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	V_{GS}=4.5V , I_D=3.25A	16.0	19.0	22.0	m ohm
		V_{GS}=4.0V , I_D=3.25A	16.5	19.5	22.5	m ohm
		V_{GS}=3.7V , I_D=3.25A	17.5	20.5	23.5	m ohm
		V_{GS}=3.1V , I_D=3.25A	19.0	23.0	27.5	m ohm
		V_{GS}=2.5V , I_D=3.25A	22.0	28.0	33.5	m ohm
g_{FS}	Forward Transconductance	V_{DS}=5V , I_D=3.25A		18		S
DYNAMIC CHARACTERISTICS [c]						
C_{ISS}	Input Capacitance	V_{DS}=10V,V_{GS}=0V f=1.0MHz		320		pF
C_{OSS}	Output Capacitance			106		pF
C_{RSS}	Reverse Transfer Capacitance			92		pF
SWITCHING CHARACTERISTICS [c]						
$t_{D(ON)}$	Turn-On Delay Time	V_{DD}=16V I_D=3.25A V_{GS}=4.0V R_{GEN}= 6 ohm		13.5		ns
t_r	Rise Time			30		ns
$t_{D(OFF)}$	Turn-Off Delay Time			19		ns
t_f	Fall Time			13.5		ns
Q_g	Total Gate Charge	V_{DS}=16V,I_D=6.5A, V_{GS}=4.0V		7.2		nC
Q_{gs}	Gate-Source Charge			1.4		nC
Q_{gd}	Gate-Drain Charge			4		nC
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
V_{SD}	Diode Forward Voltage	V_{GS}=0V,I_S=6.5A		0.89	1.2	V

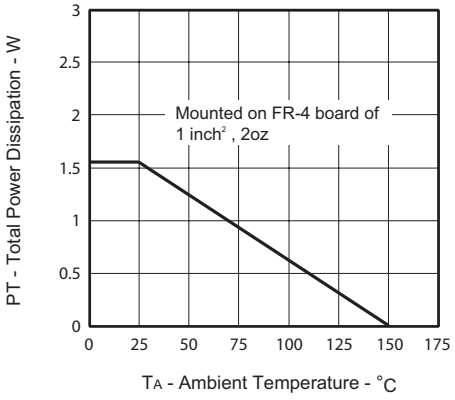
Notes

a.Surface Mounted on FR4 Board,t ≤ 10sec.
b.Pulse Test:Pulse Width ≤ 10us, Duty Cycle ≤ 1%.
c.Guaranteed by design, not subject to production testing.

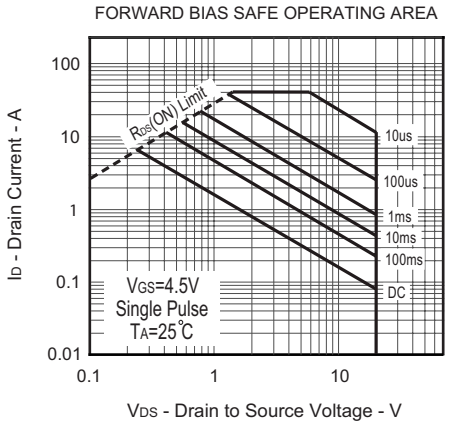
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



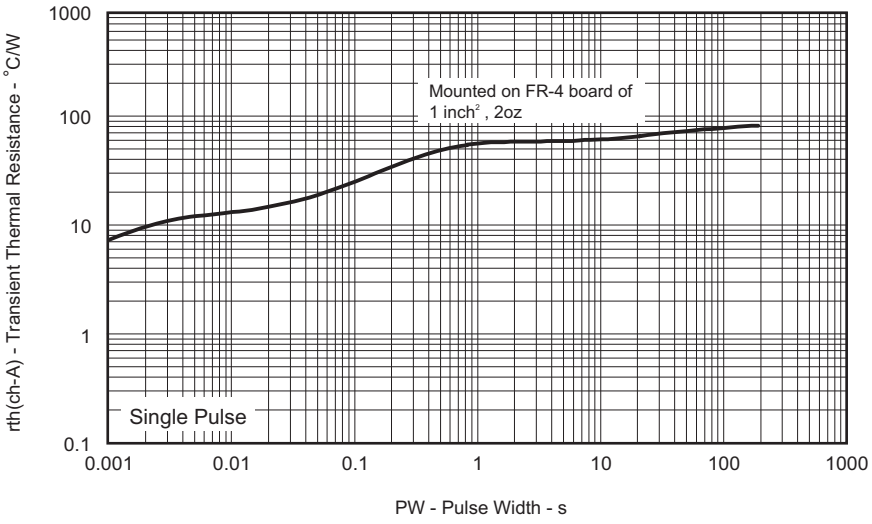
TOTAL POWER DISSIPATION vs. AMBIENT TEMPERATURE



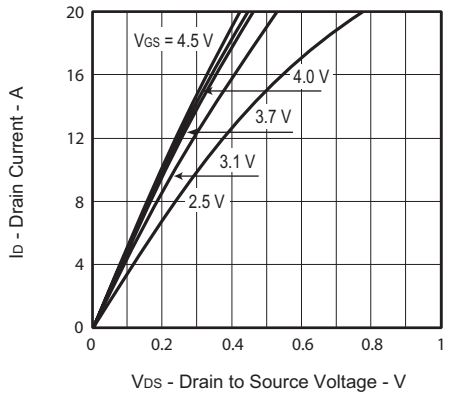
FORWARD BIAS SAFE OPERATING AREA



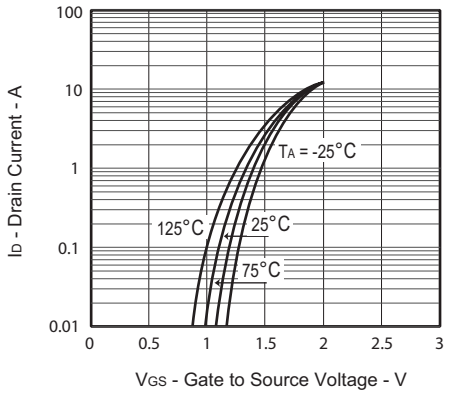
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



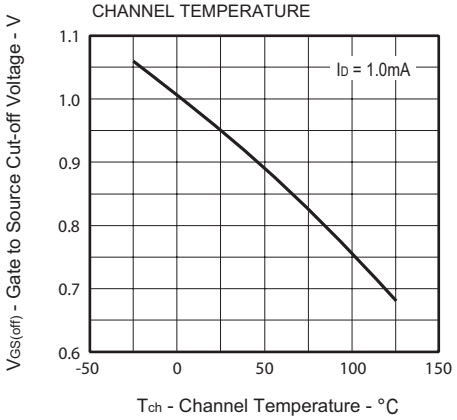
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



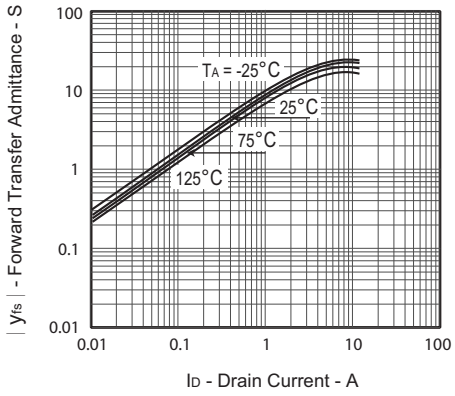
FORWARD TRANSFER CHARACTERISTICS



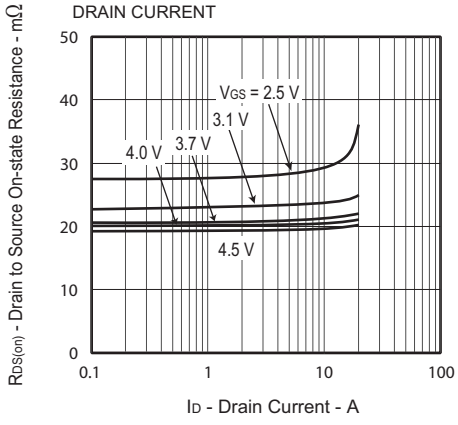
GATEBTO SOURE CUT-OFF VOLTAGE vs.
CHANNEL TEMPERATURE



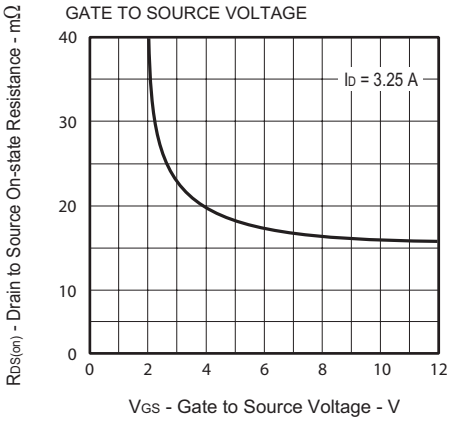
FORWARD TRANSFER ADMITTANCE vs.
DRAIN CURRENT



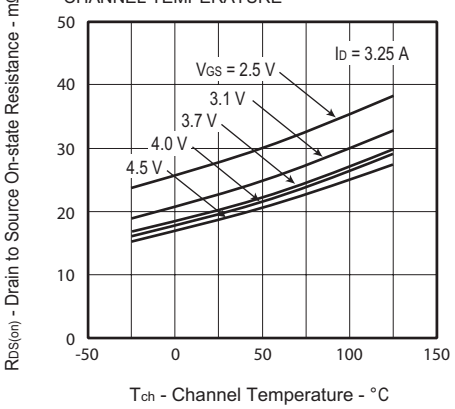
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
DRAIN CURRENT



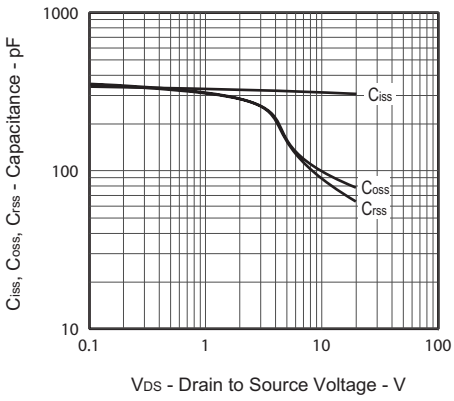
DRAIN TO SOURCE ON-STATE RESISTANCE vs.
GATE TO SOURCE VOLTAGE



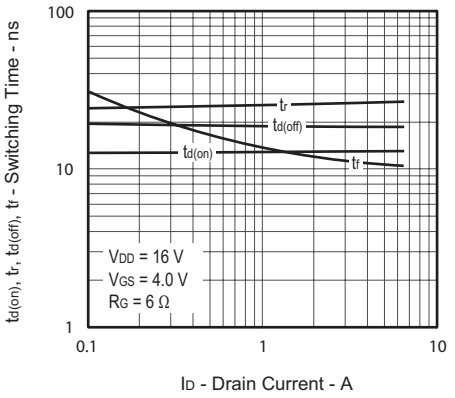
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



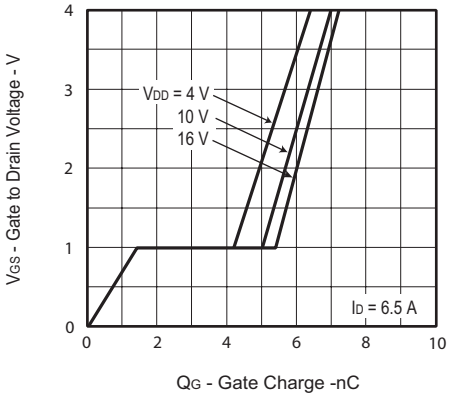
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



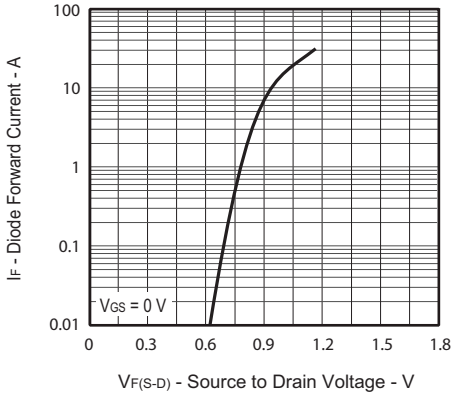
SWITCHING CHARACTERISTICS



DYNAMIC INPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



PACKAGE OUTLINE DIMENSIONS

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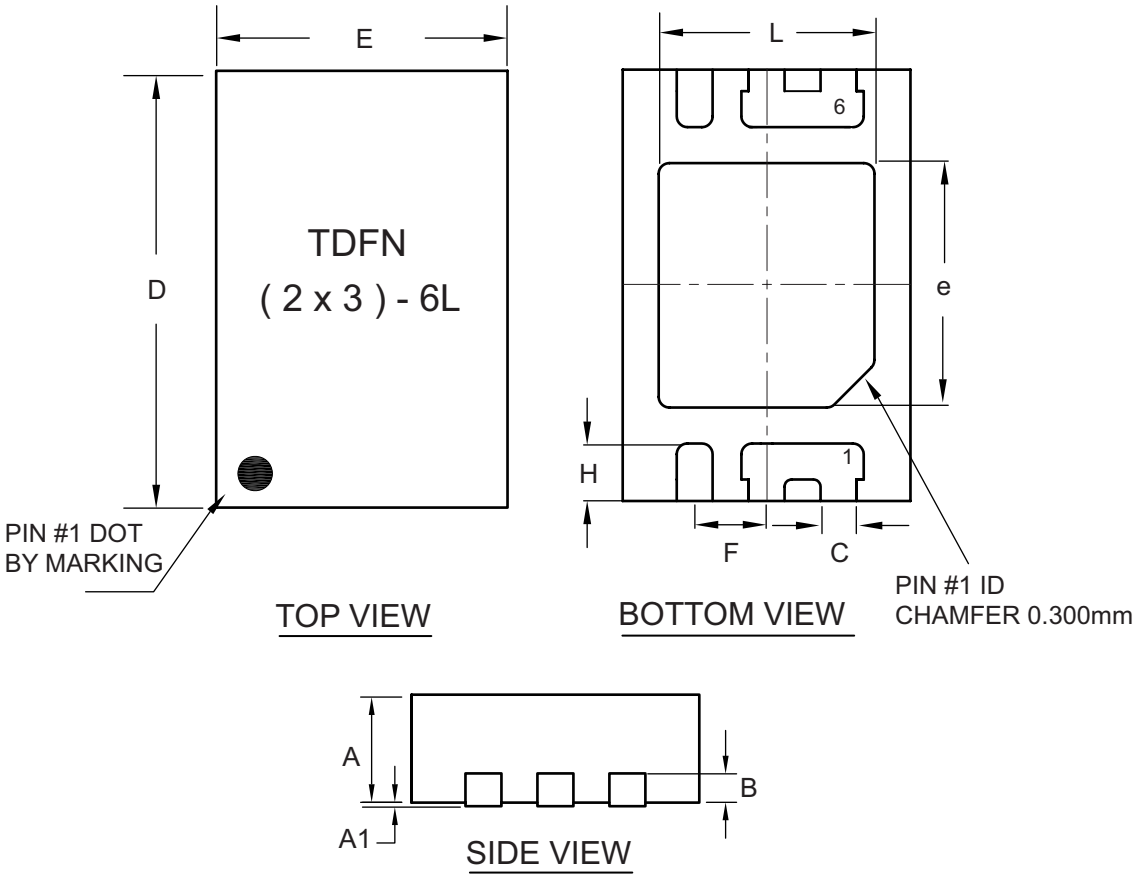

SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.700	0.800	0.028	0.031
A1	0.000	0.050	0.000	0.002
D	2.950	3.050	0.116	0.120
E	1.950	2.050	0.077	0.081
H	0.350	0.450	0.014	0.018
L	1.450	1.550	0.057	0.061
e	1.650	1.750	0.065	0.069
B	0.195	0.211	0.0076	0.008
C	0.200	0.300	0.008	0.012
F	0.500 BSC		0.020 BSC	